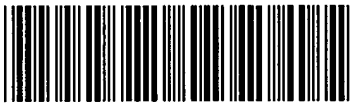


Search Notes

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10/734,136

Examiner

Anne M. Hines

Applicant(s)/Patent under
Reexamination

HAN, IN-TAEK

Art Unit

2879

SEARCHED

Class	Subclass	Date	Examiner
updated	previous search	1/24/2006	<i>AmH</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
searched East; see search history	1/24/2006	<i>AmH</i>